



2878

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RECEIVED

Applicants: James M. Holden, William A. McGahan, Richard A. Yarussi,  
Pablo I. Rovira, and Roger R. Lowe-Web  
Assignee: Nanometrics Incorporated  
Title: Apparatus And Method For The Measurement Of Diffracting Structures  
Serial No.: 09/670,000 Filing Date: September 25, 2000  
Examiner: Unknown Group Art Unit: Unknown  
Docket No.: M-9455 US

JUL - 6 2001  
TC 2800 MAIL ROOM

*7/Suppl.  
I.O.S.  
G-Stanly*

San Jose, California  
June 27, 2001  
*7-12-01*

COMMISSIONER FOR PATENTS  
Washington, D. C. 20231

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT  
UNDER 37 CFR § 1.97(b)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, the document listed on the accompanying PTO Form-1449 is called to the attention of the Examiner for the above patent application. A copy of this document is enclosed.

Citation of this document shall not be construed as:

1. an admission that the document is necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on June 27, 2001.

*Michael J. Halbert* 6-27-01  
Michael J. Halbert  
Attorney for Applicants Date of Signature

Respectfully submitted,

*Michael J. Halbert*  
Michael J. Halbert  
Attorney for Applicants  
Reg. No. 40,633

LAW OFFICES OF  
SKJERVEN MORRILL  
MacPHERSON LLP  
25 METRO DRIVE  
SUITE 700  
SAN JOSE, CA 95110  
(408) 453-9200  
FAX (408) 453-7979